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No.	Test Item	Testing conditions	Conditions of acceptability	Number of samples	Number of failures
1	Heat cycle test	(1) -40°C ~ 125°C 30minutes each (2) 800cycles	(1) No degradation of electric characteristics after test.	1	0
2	High temperature/ High humidity bias test	(1) Ambient temp. : 85°C (2) Ambient humidity : 85%RH (3) Input : 100VAC (4) Output : 0% (5) Test period : 1,000 hours	(1) No degradation of electric characteristics after test.	1	0
3	Vibration test	(1) $f=10\sim 150\text{Hz}$, 29.4m/s^2 (3G) (2) 3 minutes period (3) 60 minutes each X, Y and Z axis	(1) No degradation of electric characteristics after test. (2) No crack at solder joint. (3) No marked damage of appearance.	3	0
4	Impact test	(1) 294.2m/s^2 (30G), 11ms (2) Once each X, Y and Z axis	(1) No degradation of electric characteristics after test. (2) No crack at solder joint. (3) No marked damage of appearance.	3	0
5	Electrostatic discharge immunity test	(1) Input : 230VAC (2) Output : Rated current (3) Ambient temp. : $25\pm 10^\circ\text{C}$ (4) Contact Discharge : Level 4 (8kV) (5) Air Discharge : Level 4 (15kV) (6) Applied to Chassis, Input, Output and FG terminal	(1) No protection circuit failure. (2) No output voltage drop with control circuit failure. (3) No function fail.	1	0